Unit in mm

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 5 2 5 6 F T

VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATION

Low Noise Figure : NF = 1.5dB (f = 2GHz)

High Gain $|S_{21e}|^2 = 9.5 dB (f = 2GHz)$

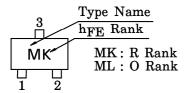
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	15	V
Collector-Emitter Voltage	v_{CEO}	7	V
Emitter-Base Voltage	$ m v_{EBO}$	1.5	V
Collector Current	$I_{\mathbf{C}}$	40	mA
Base Current	$I_{\mathbf{B}}$	20	mA
Collector Power Dissipation	PC	100	mW
Junction Temperature	$T_{ m j}$	125	°C
Storage Temperature Range	$ m T_{stg}$	-55~125	°C

1.2 ± 0.05 0.8 ± 0.05 0.22 0.32 1.4 ± 0.05 0.9 ± 0.1 .45 0.45 0.45 BASE **EMITTER** TESM COLLECTOR **JEDEC EIAJ TOSHIBA** 2-1B1A

Weight: 0.0022g

MARKING



MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	${ m f_T}$	$V_{CE}=5V$, $I_{C}=20mA$	9	12	_	GHz
I Incontion (ioin		$V_{CE}=5V$, $I_{C}=20mA$, $f=1GHz$		15	_	dB
	$ S_{21e} ^2$ (2)	$V_{CE}=5V$, $I_{C}=20mA$, $f=2GHz$	6.5	9.5	_	
Noise Figure	NF (1)	$V_{CE}=5V$, $I_{C}=5mA$, $f=1GHz$	_	1.1	_	dB
	NF (2)	$V_{CE}=5V$, $I_{C}=5mA$, $f=2GHz$	_	1.5	3	

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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = 10V, I_{E} = 0$	_	_	1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB} = 1V, I_C = 0$	_	_	1	μ A
DC Current Gain	h _{FE} (Note 1)	$V_{\rm CE}$ =5V, $I_{\rm C}$ =20mA	50	_	160	
Output Capacitance	C_{ob}	$V_{CB} = 10V, I_{E} = 0, f = 1MHz$		0.65	_	pF
Reverse Transfer Capacitance	$\mathrm{C_{re}}$	(Note 2)	1	0.5	0.95	рF

(Note 1): hFE Classification $R:50{\sim}100,~O:80{\sim}160$ (Note 2): C_{re} is measured by 3 terminal method with capacitance bridge.